

EPC2308 – Enhancement Mode Power Transistor

V_{DS} , 150 V
 $R_{DS(on)}$, 6 mΩ max

PRELIMINARY



RoHS (Pb)

(Hg) Halogen-Free

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Questions:



EPC2308
 Package size: 3 x 5 mm

Applications

- High density DC-DC from 80–100 V
- AC/DC
- Synchronous rectification from 28–54 V for chargers, adaptors, and power supplies
- Solar optimizers and microinverters
- Motor drive and DC-DC for battery-operated power tools and robots
- USB fast chargers

Benefits

- Higher Efficiency – Lower conduction and switching losses, zero reverse recovery losses
- Ultra Small Footprint – Higher power density
- Thermally enhanced QFN package with exposed top and ultra-low thermal resistances for cooler operations
- Wettable flanks and 0.6 mm between high voltage and low voltage pads to simplify assembly and inspection

Maximum Ratings			
	PARAMETER	VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	150	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	180	
I_D	Continuous ($T_A = 25^\circ\text{C}$)	48	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$)	157	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	°C
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics			
	PARAMETER	TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Case TOP)	0.5	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board (Case BOTTOM)	2.8	
$R_{\theta JA_JEDEC}$	Thermal Resistance, Junction-to-Ambient (using JEDEC 51-2 PCB)	54	
$R_{\theta JA_EVB}$	Thermal Resistance, Junction-to-Ambient (EPC90143 EVB)	23	

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$, $I_D = [\text{TBD}]$	150			V
$I_{DS(on)}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$, $V_{DS} = 120 \text{ V}$		0.003		
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.015		mA
	Gate-to-Source Forward Leakage [#]	$V_{GS} = 5 \text{ V}$, $T_J = 125^\circ\text{C}$		0.2		
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.015		
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 5 \text{ mA}$	0.7	1.2	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$, $I_D = 15 \text{ A}$		4.6	6	mΩ
V_{SD}	Source-Drain Forward Voltage [#]	$I_S = 0.5 \text{ A}$, $V_{GS} = 0 \text{ V}$		1.5		V

[#] Defined by design. Not subject to production test.

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://bit.ly/EPC2308>

Dynamic Characteristics [#] ($T_j = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 75\text{ V}, V_{GS} = 0\text{ V}$		1454	2103	pF
C_{RSS}	Reverse Transfer Capacitance			2.6		
C_{OSS}	Output Capacitance			405	592	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 1)			498		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 2)	$V_{DS} = 0 \text{ to } 75\text{ V}, V_{GS} = 0\text{ V}$		664		nC
R_G	Gate Resistance			0.4		
Q_G	Total Gate Charge	$V_{DS} = 75\text{ V}, V_{GS} = 5\text{ V}, I_D = 15\text{ A}$		10.6	13.8	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 75\text{ V}, I_D = 15\text{ A}$		3.8		
Q_{GD}	Gate-to-Drain Charge			1.3		
$Q_{G(TH)}$	Gate Charge at Threshold			2.4		
Q_{OSS}	Output Charge	$V_{DS} = 75\text{ V}, V_{GS} = 0\text{ V}$		50	61	
Q_{RR}	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Defined by design. Not subject to production test.

Note 1: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 2: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Figure 1: Typical Output Characteristics at 25°C

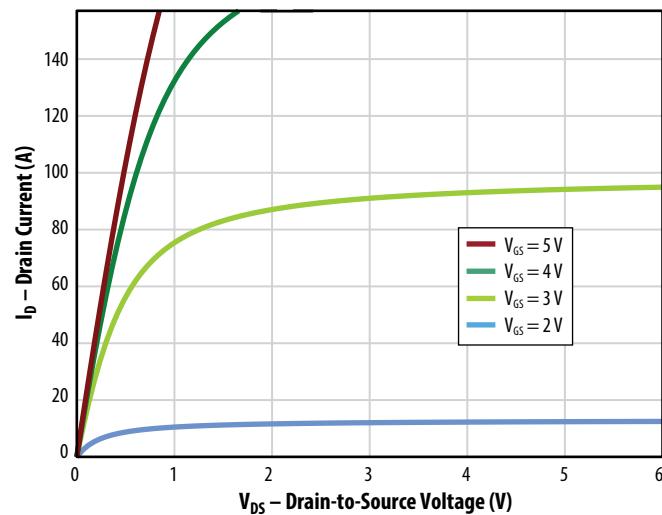


Figure 2: Typical Transfer Characteristics

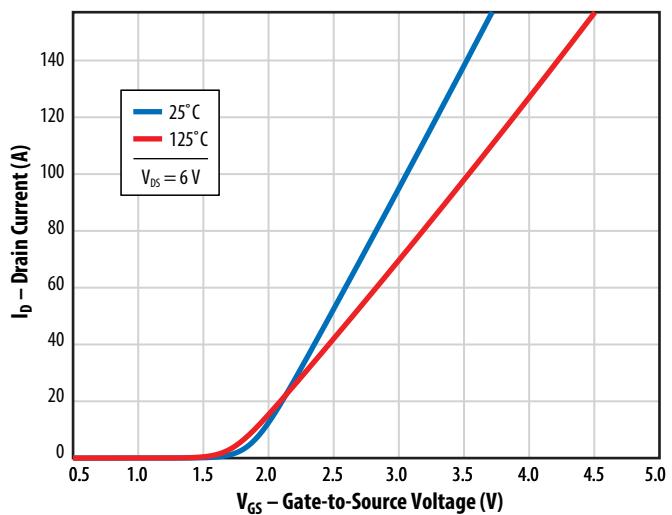


Figure 3: Typical $R_{DS(on)}$ vs. V_{GS} for Various Drain Currents

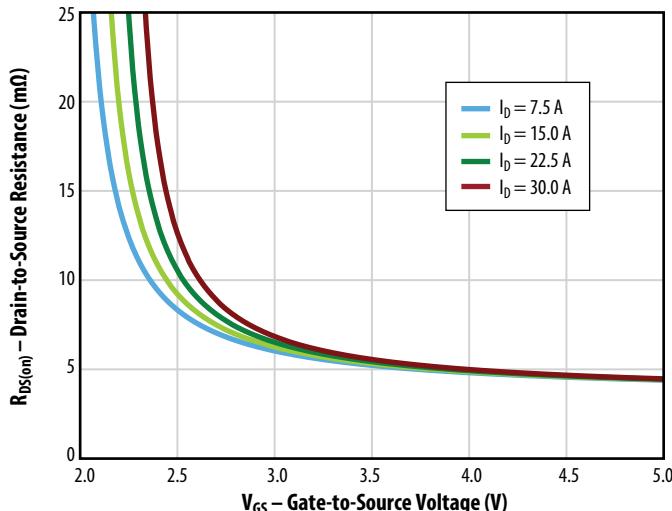


Figure 4: Typical $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

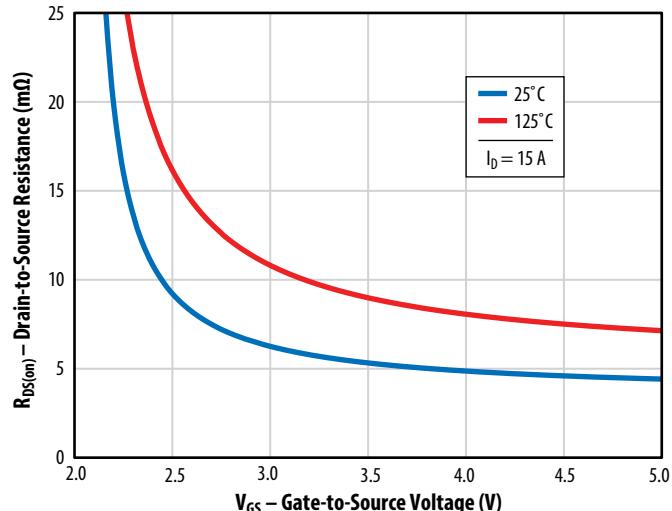
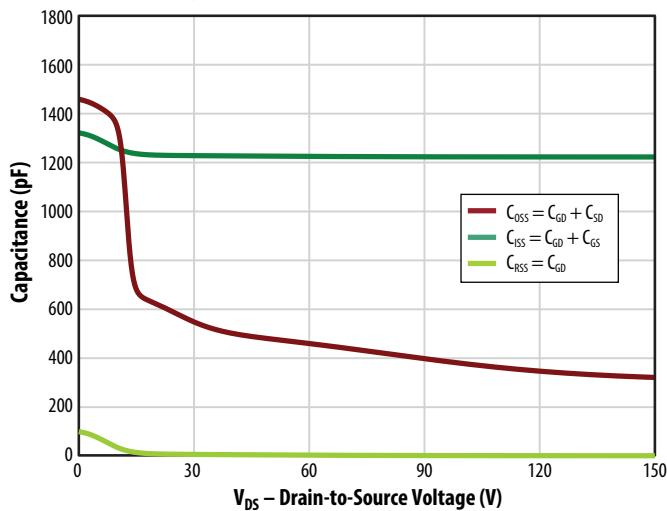
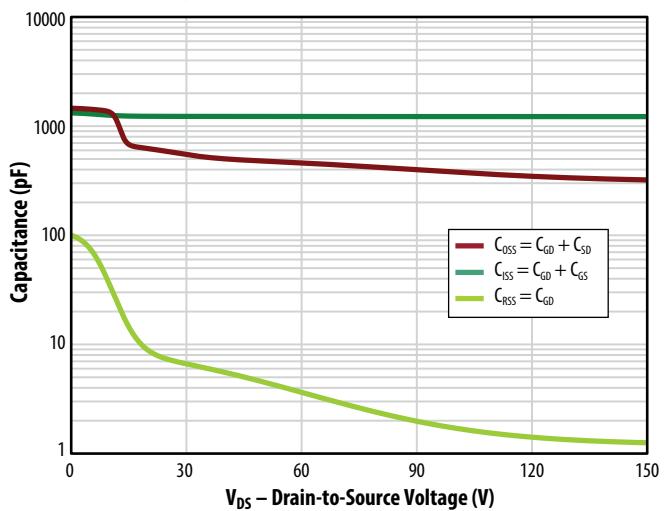
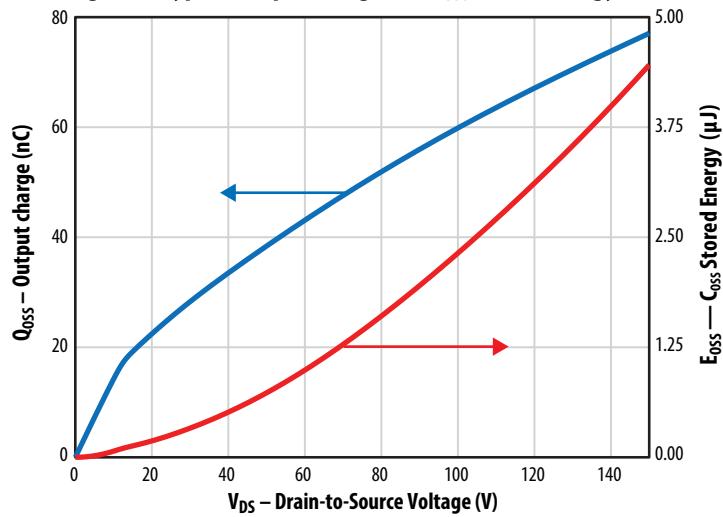
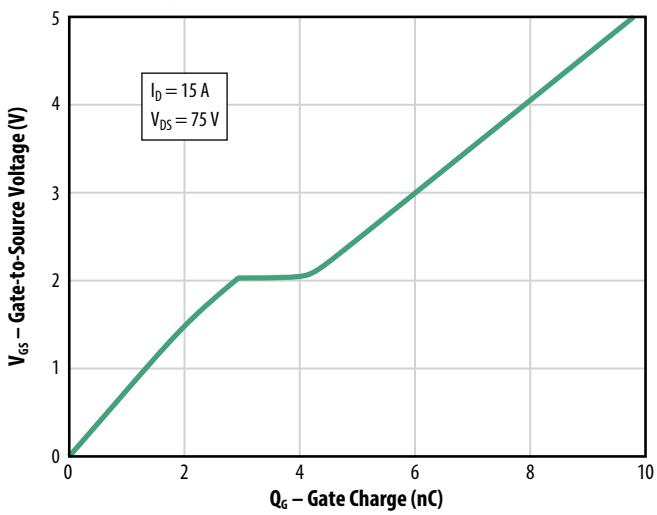
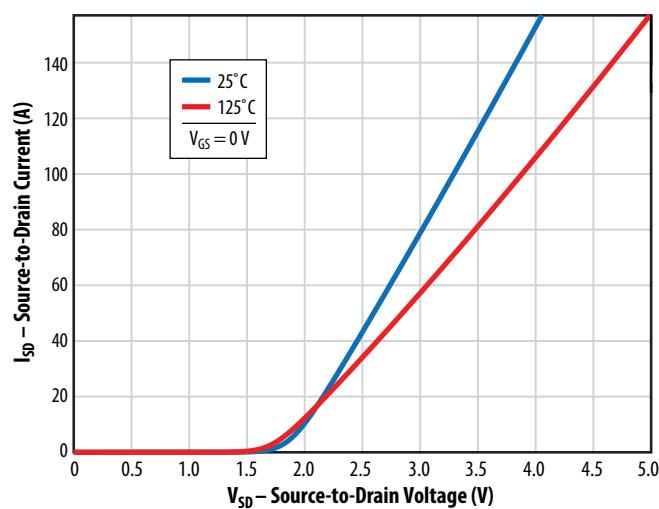


Figure 5a: Typical Capacitance (Linear Scale)**Figure 5b: Typical Capacitance (Log Scale)****Figure 6: Typical Output Charge and C_{oss} Stored Energy****Figure 7: Typical Gate Charge****Figure 8: Typical Reverse Drain-Source Characteristics**

Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0 V for OFF.

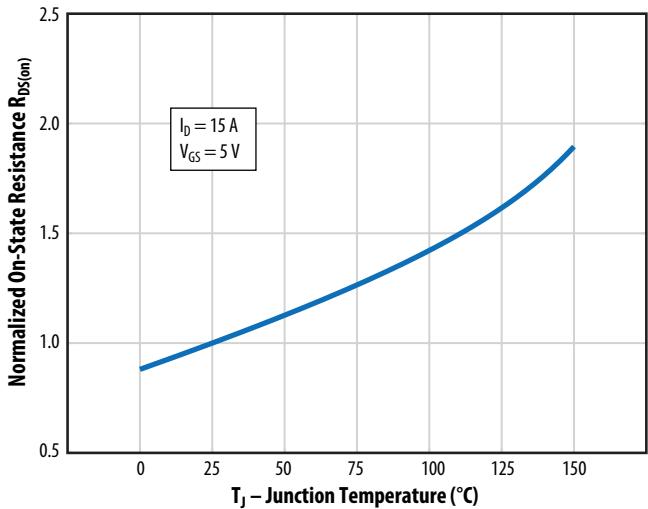
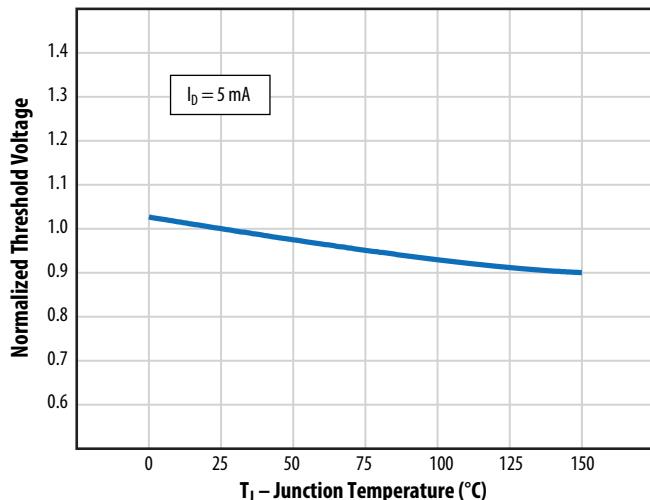
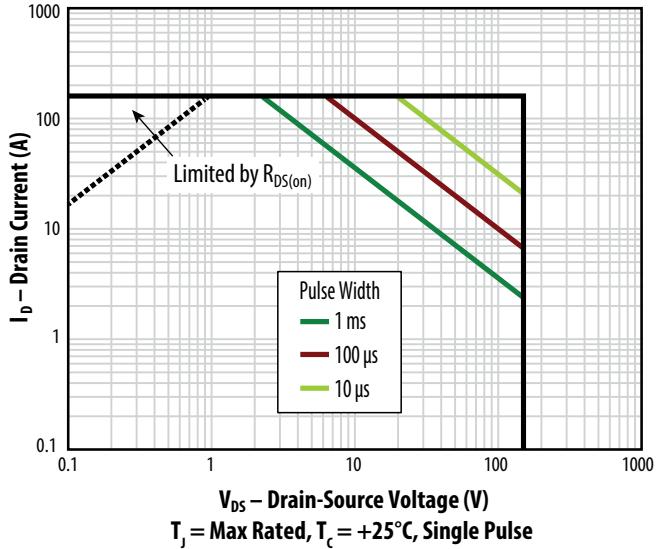
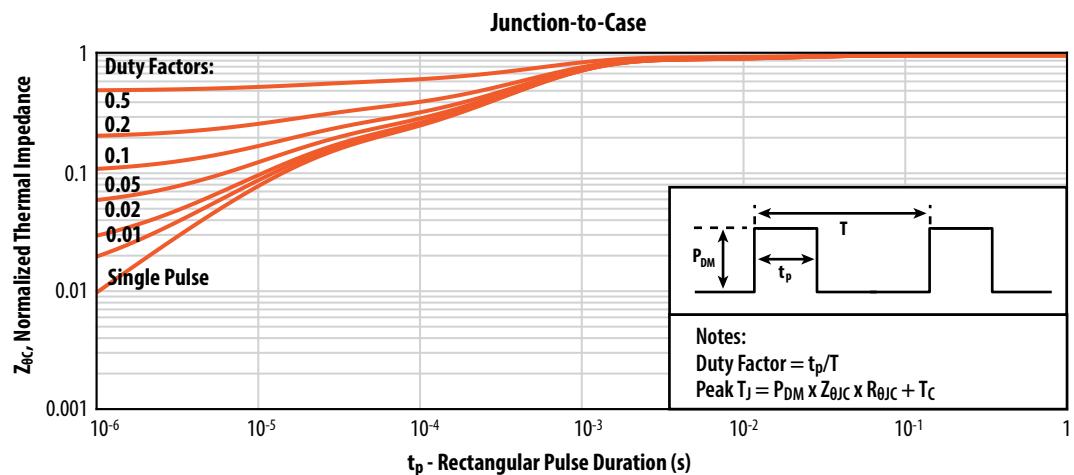
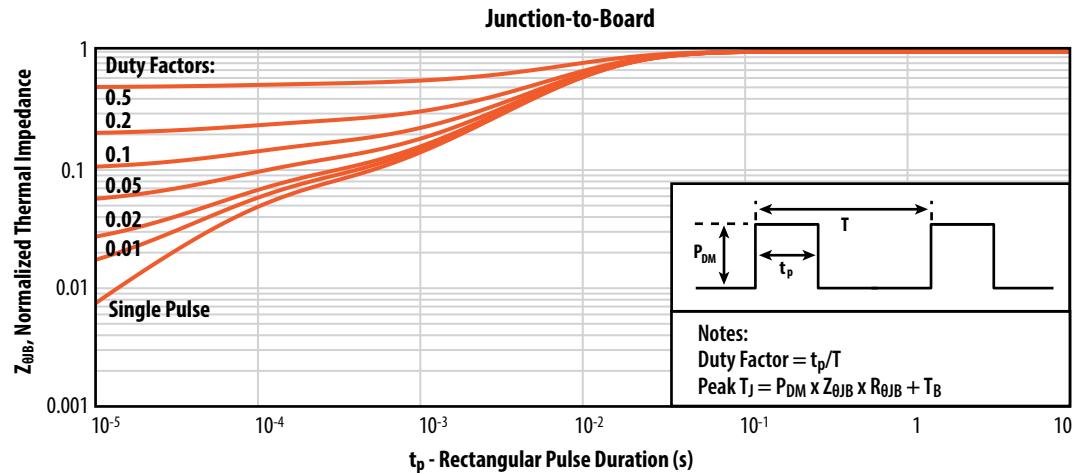
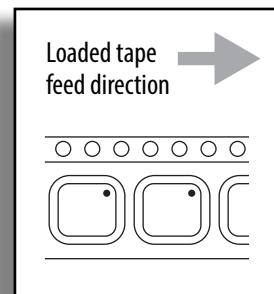
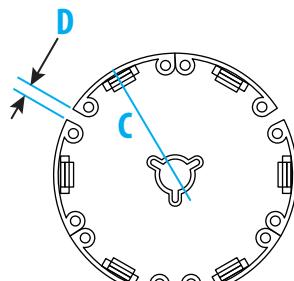
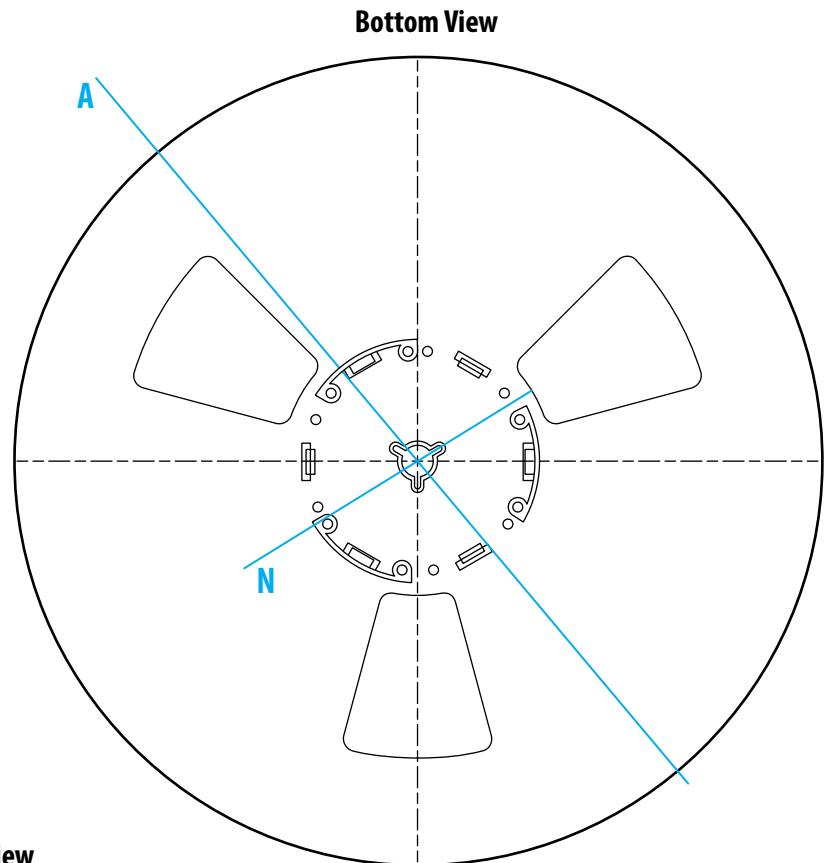
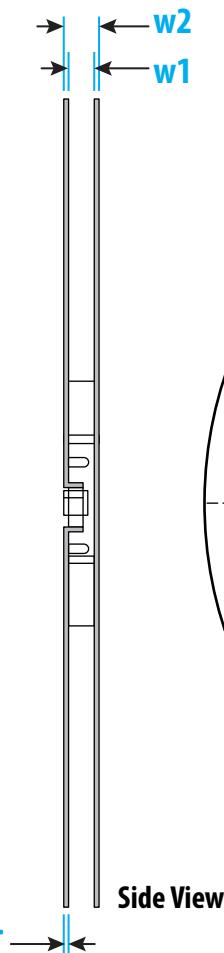
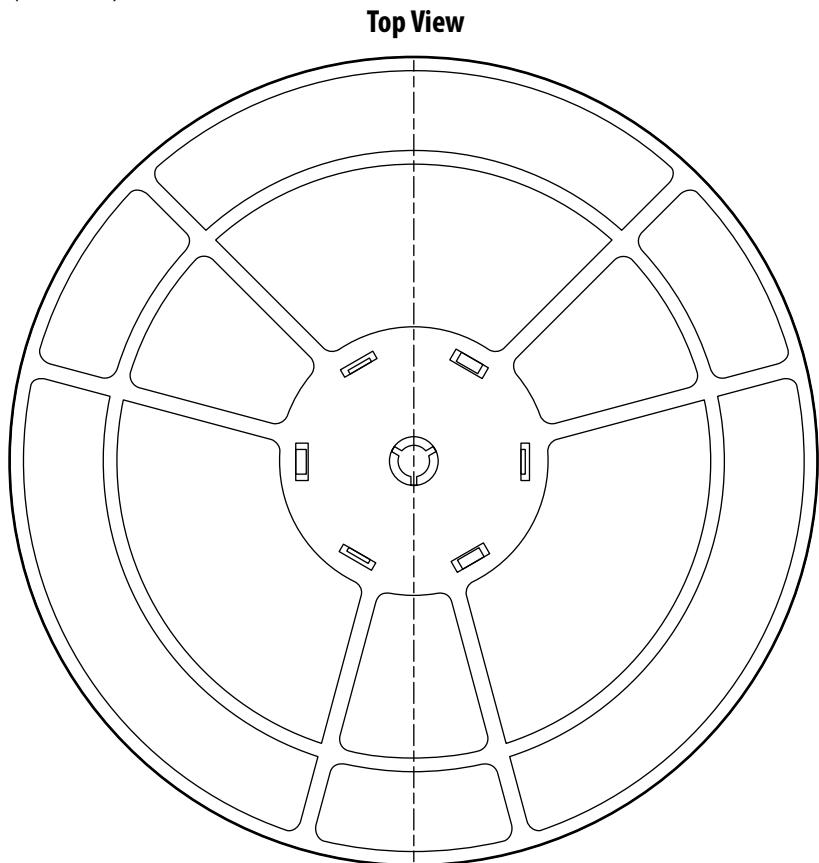
Figure 9: Typical Normalized On-State Resistance vs. Temp.

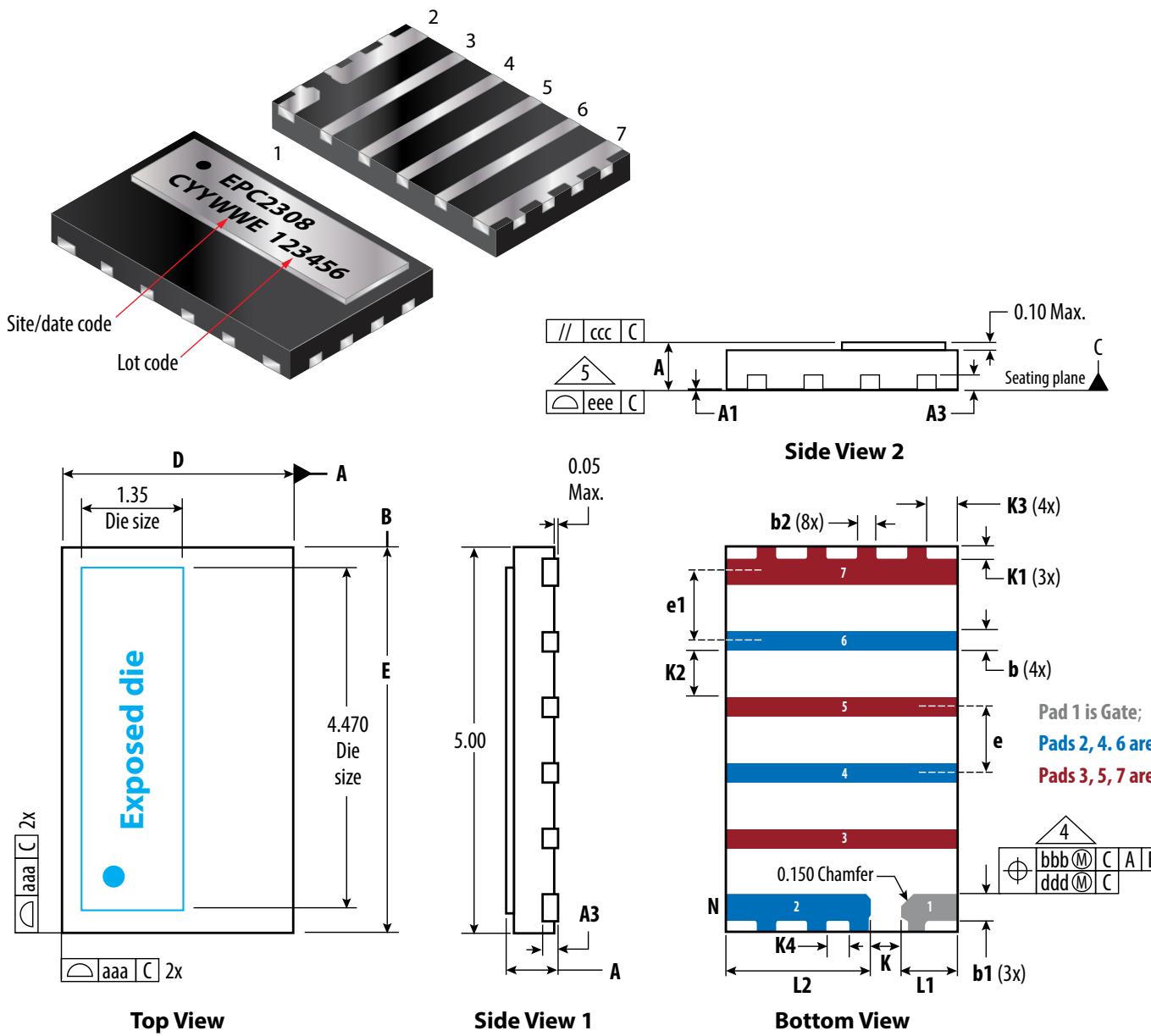
Figure 10: Typical Normalized Threshold Voltage vs. Temp.**Figure 11: Safe Operating Area****Figure 12: Transient Thermal Response Curves**

TAPE AND REEL

(units in mm)



Type	A	N	C	D	w ₁	w ₂	T
8MM	$\varnothing 330 \pm 2$	$\varnothing 100 \pm 2$	$\varnothing 13.1 \pm 0.2$	5.6 ± 0.5	$8.4 + 1.5$	14.4	2.1 ± 0.5
12MM	$\varnothing 330 \pm 2$	$\varnothing 100 \pm 2$	$\varnothing 13.1 \pm 0.2$	5.6 ± 0.5	$12.4 + 1.5$	18.4	2.1 ± 0.5
16MM	$\varnothing 330 \pm 2$	$\varnothing 100 \pm 2$	$\varnothing 13.1 \pm 0.2$	5.6 ± 0.5	$16.4 + 1.5$	22.4	2.1 ± 0.5
24MM	$\varnothing 330 \pm 2$	$\varnothing 100 \pm 2$	$\varnothing 13.1 \pm 0.2$	5.6 ± 0.5	$24.4 + 1.5$	30.4	2.1 ± 0.5



SYMBOL	Dimension (mm)			
	MIN	Nominal	MAX	Note
A	0.60	0.65	0.70	
A1	0.00	0.02	0.05	
A3		0.20 Ref		
b	0.20	0.25	0.30	4
b1	0.30	0.35	0.40	4
b2	0.20	0.25	0.30	4
D		3.00 BSC		
E		5.00 BSC		
e		0.85 BSC		
e1		0.90 BSC		
L1	0.625	0.725	0.825	
L2	1.775	1.875	1.975	

Symbol	Dimension (mm)			
	Min	Nominal	Max	Note
K	0.35	0.40	0.45	
K1	0.10	0.15	0.20	
K2	0.55	0.60	0.65	
K3	0.35	0.40	0.45	
K4	0.25	0.30	0.35	
aaa		0.05		
bbb		0.10		
ccc		0.10		
ddd		0.05		
eee		0.08		
N		15		3
NE		6		

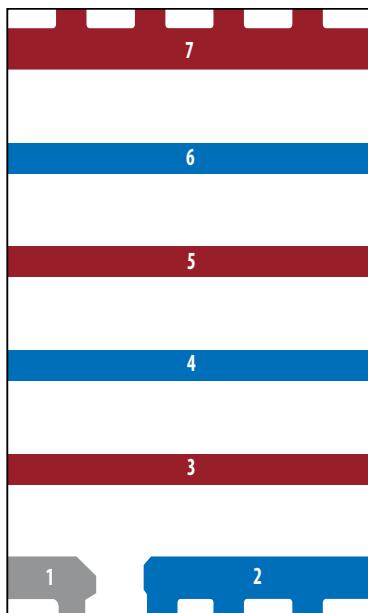
Notes:

- Dimensioning and tolerancing conform to ASME Y14.5-2009
 - All dimensions are in millimeters
 - N** is the total number of terminals

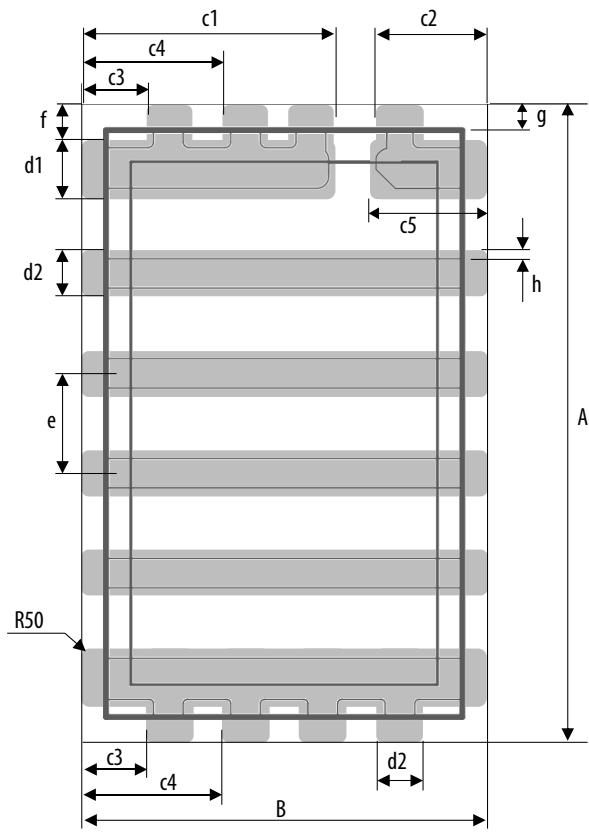
⚠ Dimension **b applies to the metallized terminal.** If the terminal has a radius on the other end of it, dimension **b** should not be measured in that radius area.

⚠ Coplanarity applies to the terminals and all the other bottom surface metallization.

TRANSPARENT VIEW



Transparent Top View

RECOMMENDED
LAND PATTERN
(units in mm)

PIN	DESCRIPTION
1	Gate
2	Source
3	Drain
4	Source
5	Drain
6	Source
7	Drain

Land pattern is solder mask defined.

It is recommended to have on-Cu trace PCB vias.

DIM	Nominal
A	5.4
B	3.4
c1	2.11
c2	0.90
c3	0.55
c4	1.20
c5	0.975
d1	0.45
d2	0.35
e	0.85
f	0.30
g	0.2
h	0.05

Additional resources available:

- Assembly resources – https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote_GaNassembly.pdf
- Library of Altium footprints for production FETs and ICs – <https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip> (for preliminary device Altium footprints, contact EPC)

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